

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 14.0003
CB Certificate No.: 20000171 ITL

Schedule Number: IECQ-L ULTW 14.0003-S Rev No.: 6 Revision Date: 2023/12/12 Page 1 of 2

Appendix-1 (20000171 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
Decap (Normal type -Au wire)	AA0093
Decap (Normal type -Cu wire)	AA0093
Decap (Special type-BGA/PCB)	AA0093
Decap (Special type-Special Epoxy)	AA0093
Take crystalline grain	AA0093
Chip Delayer (De-Al layer experiment)	AA0093
Wafer Delayer (De-Al layer experiment)	AA0093
Remove Polyimide of Wafer	AA0093
Optical microscope observing	AD0286
Stereomicroscope observing	AD0295
Taking photo of IC	AD0295
IV Curve measuring	AD0316
Scanning Electron Microscope (SEM)	AD0323
Scanning Electron Microscope (SEM)- Energy Dispersive X-ray Spectrometer (EDS) (um grade)	AD0323
Cross Section (un-precision)	AA0093
Cross Section (precision)	AA0093
Rubber Test	AD0313

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 14.0003
CB Certificate No.: 20000171 ITL

Schedule Number: IECQ-L ULTW 14.0003-S Rev No.: 6 Revision Date: 2023/12/12 Page 2 of 2

Bursting strength testing	AD0300
Optical surface measurement system (Leica DCM8 Confocal and Interferometry Microscope)	AD0345
High pressure gas & risk gas particle measuring	AD0349
FTIR Fourier-Transform Infrared spectroscopy analysis	AD0368
Liquid Particle Counter (LPC) liquid particle measuring	AD0366
Ion Chromatography analysis	AD0335
X-Ray	AD0413
X-Ray Fluorescent Analysis	AD0429
FIB Microscope Observing	AD0431

Tue Wos

Technical Reviewer of DQS:

Date: 12/12/2023

